



P-Channel Enhancement-Mode Vertical DMOS Power FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package			
				TO-39	TO-92	TO-220	DICE
-160V	12Ω	-0.75A	-2.4A	TP0616N2	TP0616N3	TP0616N5	TP0616ND
-200V	12Ω	-0.75A	-2.4A	TP0620N2	TP0620N3	TP0620N5	TP0620ND

Features

- Low threshold
- High input impedance
- Low input capacitance
- Fast switching speeds
- Low on resistance
- Freedom from secondary breakdown
- Low input and output leakage
- Complementary N- and P-channel devices

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and negative temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

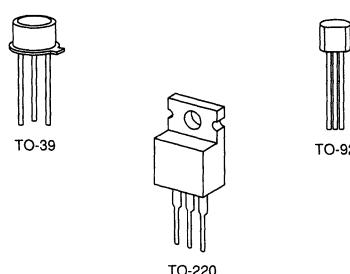
Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Applications

- Logic level interface
- Solid state relays
- Battery operated systems
- Photo voltaic drive
- Analog switch
- General purpose line driver

Package Options

(Note 1)



Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	$\pm 20V$
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

*Distance of 1.6 mm from case for 10 seconds.

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)*	Power Dissipation @ $T_C = 25^\circ\text{C}$	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}	I_{DRM}^*
TO-39	-1.0A	-1.5A	6W	21	125	-1.0A	-1.5A
TO-92	-0.4A	-0.8A	1W	125	170	-0.4A	-0.8A
TO-220	-1.0A	-2.5A	28W	2.7	70	-1.0A	-2.5A

* I_D (continuous) is limited by max rated T_j .

Electrical Characteristics (@ 25°C unless otherwise specified)

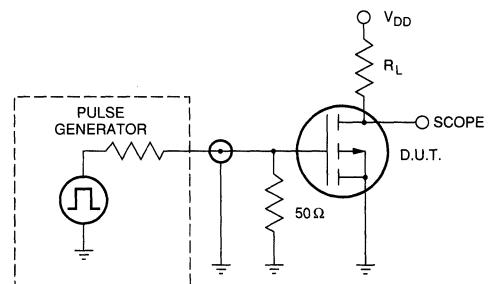
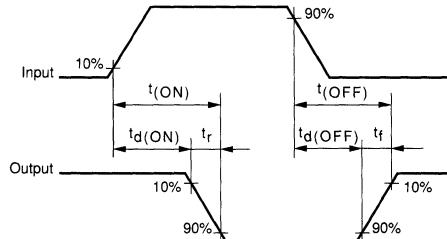
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP0620	-200		V	$V_{GS} = 0, I_D = -2.0\text{mA}$
		TP0616	-160			
$V_{GS(\text{th})}$	Gate Threshold Voltage	-1.0		-2.4	V	$V_{GS} = V_{DS}, I_D = -1.0\text{mA}$
$\Delta V_{GS(\text{th})}$	Change in $V_{GS(\text{th})}$ with Temperature			-4.5	mV/°C	$V_{GS} = V_{DS}, I_D = -1.0\text{mA}$
I_{GSS}	Gate Body Leakage			-100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0$
I_{DSS}	Zero Gate Voltage Drain Current			-10	μA	$V_{GS} = 0, V_{DS} = \text{Max Rating}$
				-1	mA	$V_{GS} = 0, V_{DS} = 0.8 \text{ Max Rating}$ $T_A = 125^\circ\text{C}$
$I_{D(\text{ON})}$	ON-State Drain Current	-0.25			A	$V_{GS} = -5\text{V}, V_{DS} = -25\text{V}$
		-0.75				
$R_{DS(\text{ON})}$	Static Drain-to-Source ON-State Resistance		12	15	Ω	$V_{GS} = -5\text{V}, I_D = -0.1\text{mA}$
			9	12		
$\Delta R_{DS(\text{ON})}$	Change in $R_{DS(\text{ON})}$ with Temperature			1.7	%/°C	$V_{GS} = -10\text{V}, I_D = -0.2\text{A}$
G_{FS}	Forward Transconductance	100			mΩ	$V_{DS} = -25\text{V}, I_D = -0.2\text{A}$
C_{ISS}	Input Capacitance		85	150	pF	$V_{GS} = 0, V_{DS} = -25\text{V}$ $f = 1 \text{ MHz}$
C_{OSS}	Common Source Output Capacitance		50	85		
C_{RSS}	Reverse Transfer Capacitance		10	35		
$t_{d(\text{ON})}$	Turn-ON Delay Time			10	ns	$V_{DD} = -25\text{V}$ $I_D = -1.0\text{A}$ $R_S = 50\Omega$
t_r	Rise Time			15		
$t_{d(\text{OFF})}$	Turn-OFF Delay Time			20		
t_f	Fall Time			15		
V_{SD}	Diode Forward Voltage Drop			-1.8	V	$V_{GS} = 0, I_{SD} = 0.5\text{A}$
t_{rr}	Reverse Recovery Time		300		ns	$V_{GS} = 0, I_{SD} = 0.5\text{A}$

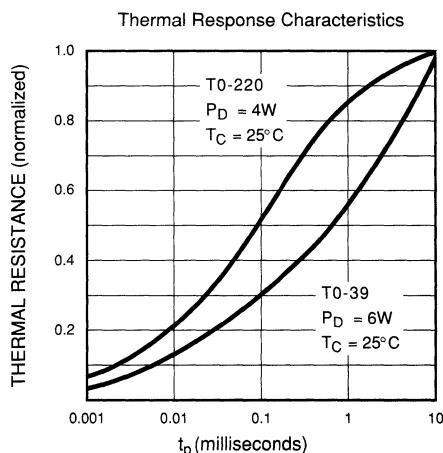
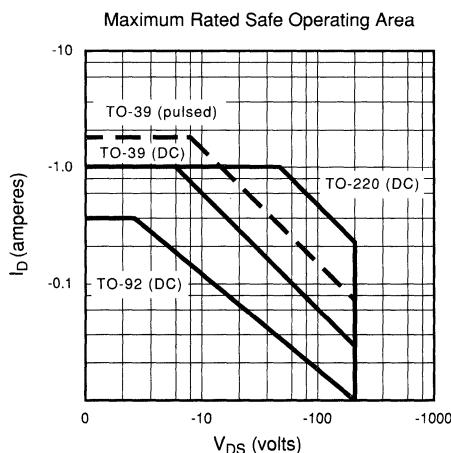
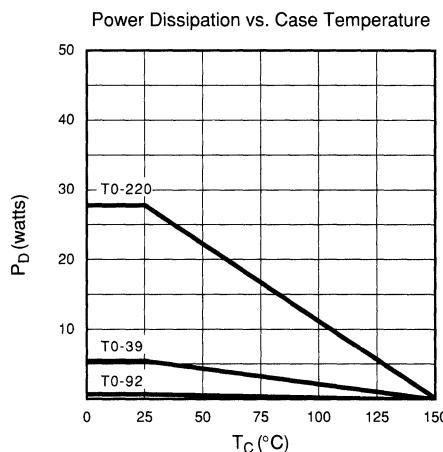
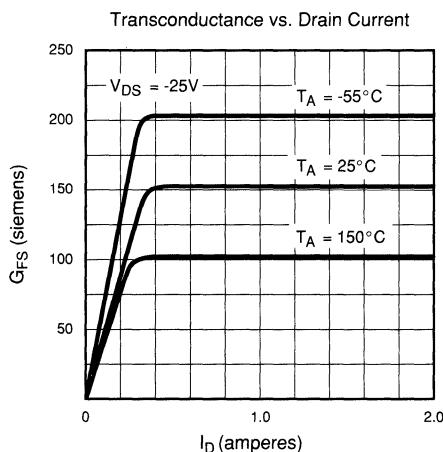
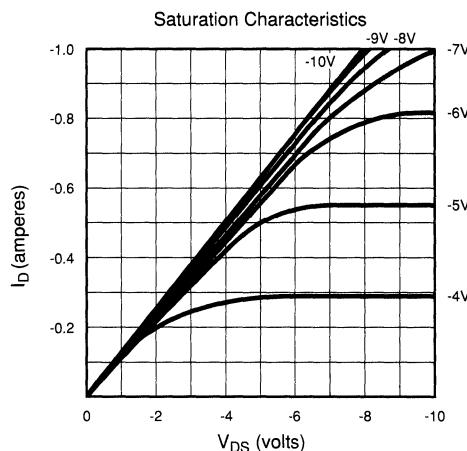
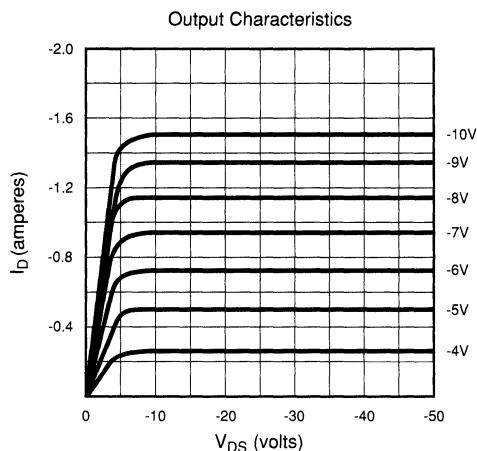
Note 1: All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)

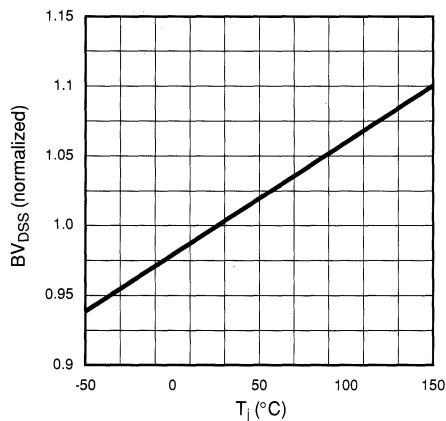
Note 2: All A.C. parameters sample tested.

Switching Waveforms and Test Circuit

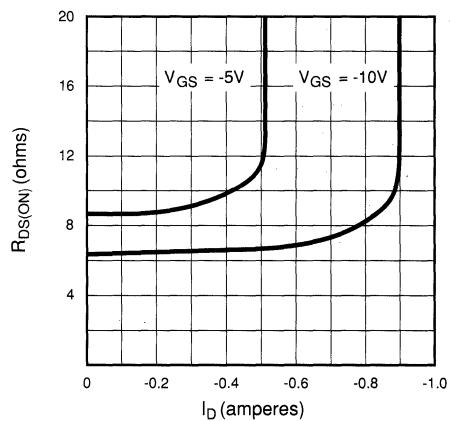


Typical Performance Curves

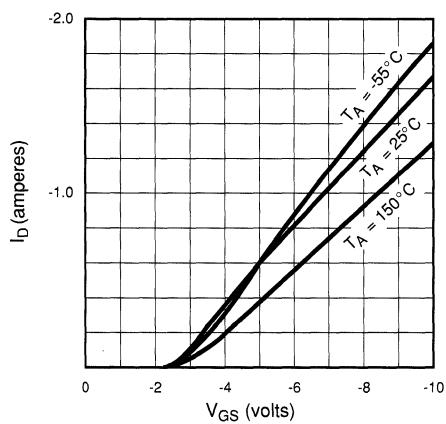
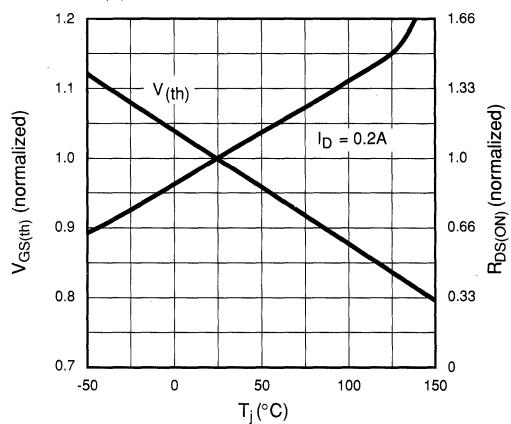


BV_{DSS} Variation with Temperature

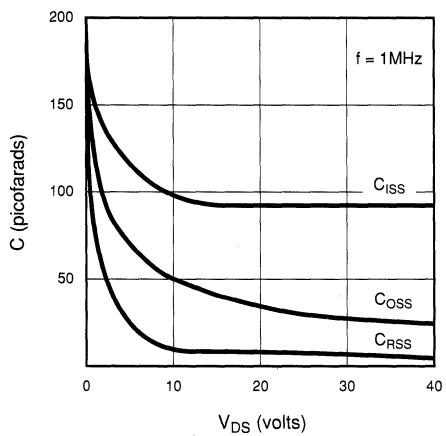
On-Resistance vs. Drain Current



Transfer Characteristics

 $V_{(th)}$ and R_{DS} Variation with Temperature

Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics

